

Contents

Section I Measurement Characteristics

- 1 Characteristics of Instrumentation *R. John Hansman, Jr.* 1-1
- 2 Operational Modes of Instrumentation *Richard S. Figliola* 2-1
- 3 Static and Dynamic Characteristics of Instrumentation
Peter H. Sydenham 3-1
- 4 Measurement Accuracy *Ronald H. Dieck* 4-1
- 5 Measurement Standards *DeWayne B. Sharp* 5-1

Section II Spatial Variables Measurement

- 6 Displacement Measurement, Linear and Angular
 - 6.1 Resistive Displacement Sensors *Keith Antonelli, James Ko, and Shyan Ku* 6-2
 - 6.2 Inductive Displacement Sensors *Halit Eren* 6-15
 - 6.3 Capacitive Sensors—Displacement *Halit Eren and Wei Ling Kong* 6-37
 - 6.4 Piezoelectric Transducers and Sensors *Ahmad Safari, Victor F. Janas, Amit Bandyopadhyay, and Andrei Kholkin* 6-53
 - 6.5 Laser Interferometer Displacement Sensors *Bernhard Günther Zagar* 6-65
 - 6.6 Bore Gaging Displacement Sensors *Viktor P. Astakhov* 6-78
 - 6.7 Time-of-Flight Ultrasonic Displacement Sensors
Teklic Ole Pedersen and Nils Karlsson 6-92
 - 6.8 Optical Encoder Displacement Sensors *J. R. René Mayer* 6-98
 - 6.9 Magnetic Displacement Sensors *David S. Nyce* 6-119
 - 6.10 Synchro/Resolver Displacement Sensors
Robert M. Hyatt, Jr. and David Dayton 6-128
 - 6.11 Optical Fiber Displacement Sensors
Richard O. Claus, Vikram Bhatia, and Anbo Wang 6-141
 - 6.12 Optical Beam Deflection Sensing *Grover C. Wetsel* 6-156

7	Thickness Measurement	John C. Brasunas, G. Mark Cushman, and Brook Lakew.....	7-1
8	Proximity Sensing for Robotics	R.E. Saad, A. Bonen, K.C. Smith, and B. Benhabib	8-1
9	Distance	W. John Ballantyne.....	9-1
10	Position, Location, Altitude Measurement		
10.1	Altitude Measurement	Dimitris E. Manolakis.....	10-1
10.2	Attitude Measurement	Mark A. Stedham, Partha B. Banerjee, Seiji Nishfuji, and Shogo Tanaka.....	10-17
10.3	Inertial Navigation	Halit Eren and C.C. Fung	10-34
10.4	Satellite Navigation and Radiolocation	Halit Eren and C.C. Fung.....	10-48
10.5	Occupancy Detection	Jacob Fraden	10-62
11	Level Measurement	Detlef Brumbi	11-1
12	Area Measurement	Charles B. Coulbourn and Wolfgang P. Buerner	12-1
13	Volume Measurement	René G. Aarnink and Hessel Wijkstra	13-1
14	Angle Measurement	Robert J. Sandberg.....	14-1
15	Tilt Measurement	Adam Chrzanowski and James M. Secord	15-1
16	Velocity Measurement	Charles P. Pinney and William E. Baker	16-1
17	Acceleration, Vibration, and Shock Measurement	Halit Eren	17-1

Section III Time and Frequency Measurement

18	Time Measurement	Michael A. Lombardi.....	18-1
19	Frequency Measurement	Michael A. Lombardi.....	19-1

Section IV Mechanical Variables Measurement — Solid

20	Mass and Weight Measurement	Mark Fritz and Emil Hazarian.....	20-1
21	Density measurement	Halit Eren	21-1

22	Strain Measurement	<i>Christopher S. Lynch</i>	22-1
23	Force Measurement	<i>M.A. Elbestawi</i>	23-1
24	Torque and Power Measurement	<i>Ivan J. Garshelis</i>	24-1
25	Tactile Sensing	<i>R.E. Saad, A. Bonen, K. C. Smith, and B. Benhabib</i>	25-1

V Mechanical Variables Measurement — Fluid

26	Pressure and Sound Measurement		
26.1	Pressure Measuremnt	<i>Kevin H.-L. Chau</i>	26-1
26.2	Vacuum Measurement	<i>Ron Goehner, Emil Drubetsky, Howard M. Brady, and William H. Bayles, Jr.</i>	26-11
26.3	Ultrasound Measurement	<i>Peder C. Pedersen</i>	26-33
27	Acoustic Measurement	<i>Per Rasmussen</i>	27-1
28	Flow Measurement		
28.1	Differential Pressure Flowmeters	<i>Richard Thorn</i>	28-2
28.2	Variable Area Flowmeters	<i>Adrian Melling, Herbert Köchner, and Reinhard Haak</i>	28-13
28.3	Positive Displacement Flowmeters	<i>Zaki D. Husain and Donald J. Wass</i>	28-33
28.4	Turbine and Vane Flowmeters	<i>David Wadlow</i>	28-40
28.5	Impeller Flowmeters	<i>Harold M. Miller</i>	28-57
28.6	Electromagnetic Flowmeters	<i>Halit Eren</i>	28-63
28.7	Ultrasonic Flowmeters	<i>Hans-Peter Vaterlaus, Thomas Hossle, Paolo Giordano, and Christophe Bruttin</i>	28-74
28.8	Vortex Shedding Flowmeters	<i>Wade M. Mattar and James H. Vignos</i>	28-89
28.9	Thermal Mass Flow Sensors	<i>Nam-Trung Nguyen</i>	28-99
28.10	Coriolis Effect Mass Flowmeters	<i>Jesse Yoder</i>	28-118
28.11	Drag Force Flowmeters	<i>Rekha Philip-Chandy, Roger Morgan, Patricia J. Scully</i>	28-122
29	Point Velocity Measurement		
29.1	Pitot Probe Anemometry	<i>John A. Kleppe</i>	29-1
29.2	Thermal Anemometry	<i>John G. Olin</i>	29-18
29.3	Laser Anemometry	<i>Rajan K. Menon</i>	29-37
30	Viscosity Measurement	<i>G. E. Leblanc, R. A. Secco, M. Kostic</i>	30-1
31	Surface Tension Measurement	<i>David B. Thiessen, Kin F. Man</i>	31-1

VI Mechanical Variables Measurement — Thermal

32 Temperature Measurement

32.1 Bimaterials Thermometers *Robert J. Stephenson, Armelle M. Moulin, and Mark E. Welland* 32-2

32.2 Resistive Thermometers *Jim Burns* 32-13

32.3 Thermistor Thermometers *Meyer Sapoff* 32-25

32.4 Thermocouple Thermometers *R. P. Reed* 32-41

32.5 Semiconductor Junction Thermometers *Randy Frank* 32-74

32.6 Infrared Thermometers *Jacob Fraden* 32-87

32.7 Pyroelectric Thermometers *Jacob Fraden* 32-109

32.8 Liquid-in-Glass Thermometers *J. V. Nicholas* 32-117

32.9 Manometric Thermometers *Franco Pavese* 32-129

32.10 Temperature Indicators *Jan Stasiek, Tolestyn Madaj, Jaroslaw Mikielewicz* 32-136

32.11 Fiber-Optic Thermometers *Brian Culshaw* 32-152

33 Thermal Conductivity Measurement

William A. Wakeham and Marc J. Assael 33-1

34 Heat Flux *Thomas E. Diller* 34-1

35 Thermal Imaging *Herbert M. Runciman* 35-1

36 Calorimetry Measurement *Sander van Herwaarden* 36-1

VII Electromagnetic Variables Measurement

37 Voltage Measurement

37.1 Meter Voltage Measurement *Alessandro Ferrero* 37-1

37.2 Oscilloscope Voltage Measurement *Jerry Murphy* 37-22

37.3 Inductive Capacitive Voltage Measurement *Cipriano Bartoletti, Luca Podestà, and Giancarlo Sacerdoti* 37-42

38 Current Measurement *Douglas P. McNutt* 38-1

39 Power Measurement *Pasquale Arpaia, Francesco Avallone, Aldo Baccigalupi, Claudio De Capua, Carmine Landi* 39-1

40 Power Factor Measurement *Michael Z. Lowenstein* 40-1

41 Phase Measurement *Peter O'Shea* 41-1

42	Energy Measurement	<i>Arnaldo Brandolini and Alessandro Gandelli</i>	42-1
43	Electrical Conductivity and Resistivity	<i>Michael B. Heaney</i>	43-1
44	Charge Measurement	<i>Saps Buchman, John Mester, and T. J. Sumner</i> ...	44-1
45	Capacitance and Capacitance Measurements	<i>Halit Eren and James Goh</i>	45-1
46	Permittivity Measurement	<i>Devendra K. Misra</i>	46-1
47	Electric Field Strength	<i>David A. Hill and Motohisa Kanda</i>	47-1
48	Magnetic Field Measurement	<i>Steven A. Macintyre</i>	48-1
49	Permeability and Hysteresis Measurement	<i>Jeff P. Anderson and Richard J. Blotzer</i>	49-1
50	Inductance Measurement	<i>Michał Szyper</i>	50-1
51	Immittance Measurement	<i>Achim Dreher</i>	51-1
52	Q Factor Measurement	<i>Albert D. Helfrick</i>	52-1
53	Distortion Measurement	<i>Michael F. Toner and Gordon W. Roberts</i>	53-1
54	Noise Measurement	<i>W. Marshall Leach, Jr.</i>	54-1
55	Microwave Measurement	<i>A. Dehé, K. Beilenhoff, K. Fricke, H. Klingbeil, V. Krozer, H. L. Hartnagel</i>	55-1

VIII Optical Variables Measurement

56	Photometry and Radiometry		
56.1	Photoconductive Sensors	<i>Fritz Schuermeyer and Thad Pickenpaugh</i>	56-1
56.2	Photojunction Sensors	<i>Michael R. Squillante and Kanai S. Shah</i>	56-9
56.3	Charge-Coupled Devices	<i>J.A. Nousek, M.W. Bautz, B.E. Burke, J.A. Gregory, R.E. Griffiths, R.L. Kraft, H.L. Kwok, D.H. Lumb</i>	56-21
57	Densitometry Measurement	<i>Joseph H. Altman</i>	57-1
58	Colorimetry	<i>Robert T. Marcus</i>	58-1

59	Optical Loss	<i>Halit Eren</i>	59-1
60	Polarization Measurement	<i>Soe-Mie F. Nee</i>	60-1
61	Refractive Index Measurement	<i>G. H. Meeten</i>	61-1
62	Turbidity Measurement	<i>Daniel Harrison and Michael Fisch</i>	62-1
63	Laser Output Measurement	<i>Haiyin Sun</i>	63-1
64	Vision and Image Sensors	<i>Stanley S. Ipson and Chima Okereke</i>	64-1

IX Radiation Measurement

65	Radioactivity Measurement	<i>Bert M. Coursey</i>	65-1
66	Radioactivity Measurement	<i>Larry A. Franks, Ralph B. James, and Larry S. Darken</i>	66-1
67	Charged Particle Measurement	<i>John C. Armitage, Madhu S. Dixit, Jacques Dubeau, Hans Mes, and F. Gerald Oakham</i>	67-1
68	Neutron Measurement	<i>Steven M. Grimes</i>	68-1
69	Dosimetry Measurement	<i>Brian L. Justus, Mark A. Miller, and Alan L. Huston</i>	69-1

X Chemical Variables Measurement

70	Composition Measurement		
70.1	Electrochemical Composition Measurement	<i>Michael J. Schöning, Olaf Glück, and Marion Thust</i>	70-1
70.2	Thermal Composition Measurement	<i>Mushtaq Ali, Behrooz Pahlavanpour, and Maria Eklund</i>	70-49
70.3	Kinetic Methods	<i>E.E. Uzgis and J.Y. Gui</i>	70-61
70.4	Chromatography Composition Measurement	<i>Behrooz Pahlavanpour, Mushtaq Ali, and C.K. Laird</i>	70-74
71	pH Measurement		
		<i>Norman F. Sheppard, Jr. and Anthony Guiseppi-Elie</i>	71-1
72	Humidity and Moisture Measurement	<i>Gert J.W. Vischer</i>	72-1

73	Environmental Measurement	
73.1	Meteorological Measurement	<i>John D. Garrison and Stephen B. W. Roeder</i>73-1
73.2	Air Pollution Measurement	<i>Michael Bennett</i>73-16
73.3	Water Quality Measurement	<i>Kathleen M. Leonard</i>73-32
73.4	Satellite Imaging and Sensing	<i>Jacqueline Le Moigne and Robert F. Crompt</i>73-42

XI Biomedical Variables Measurement

74	Biopotentials and Electrophysiology Measurement	
	<i>Nitish V. Thakor</i>	74-1
75	Blood Pressure Measurement	
	<i>Shyam Rithalia, Mark Sun, and Roger Jones</i>	75-1
76	Blood Flow Measurements	<i>Per Ask and P. Åke Öberg</i>
		76-1
77	Ventilation Measurement	<i>L. Basano and P. Ottonello</i>
		77-1
78	Blood Chemistry Measurement	<i>Terry L. Rusch and Ravi Sankar</i>
		78-1
79	Medical Imaging	<i>James T. Dobbins III, Sean M. Hames, Bruce H. Hasegawa, Timothy R. DeGrado, James A. Zagzebski, and Richard Frayne</i>
		79-1

XII Signal Processing

80	Amplifiers and Signal Conditioners	<i>Ramón Pallás-Areny</i>
		80-1
81	Modulation	<i>David M. Beams</i>
		81-1
82	Filters	<i>Rahman Jamal and Robert Steer</i>
		82-1
83	Spectrum Analysis and Correlation	
83.1	FFT Spectrum Analysis and Correlation	<i>Ronney B. Panerai</i>
		83-1
83.2	RF/Microwave Spectrum Analysis	<i>A. Ambrosini, C. Bortolotti, N. D'Amico, G. Grueff, S. Mariotti, S. Montebugnoli, A. Orfei, and G. Tomassetti</i>
		83-16
84	Applied Intelligence Processing	
	<i>Peter H. Sydenham and Rodney Pratt</i>	84-1
85	Analog-to-Digital Converters	<i>E. B. Loewenstein</i>
		85-1
86	Computers	<i>A. M. MacLeod, P.F. Martin, and W.A. Gillespie</i>
		86-1

87 Telemetry *Albert Lozano-Nieto* 87-1

88 Sensor Networks and Communication *Robert M. Crovella* 88-1

89 Electromagnetic Compatibility

89.1 Grounding and Shielding in Industrial Electronic Systems
Daryl Gerke, and William Kimmel.....89-1

89.2 EMI and EMC Test Methods *Jeffrey P. Mills*.....89-12

XIII Displays

90 Human Factors in Displays *Steven A. Murray, Barrett S. Caldwell* 90-1

91 Cathode Ray Tube Displays *Christopher J. Sherman* 91-1

92 Liquid Crystal Displays *Kalluri R. Sarma* 92-1

93 Plasma-Driven Flat Panel Displays *Robert T. McGrath, Ramanapathy Veerasingam, William C. Moffatt, and Robert B. Campbell* 93-1

94 Electroluminescent Displays *William A. Barrow* 94-1

95 Light-Emitting Diode Displays *Mohammad A. Karim* 95-1

96 Reading/Recording Devices

96.1 Graphic Recorders *Herman Vermariën*96-1

96.2 Data Acquisition Systems *Edward McConnell*.....96-10

96.3 Magnetic and Optical Recorders *Yufeng Li*96-22

XIV Control

97 PID Control *F. Greg Shinskey*..... 97-1

98 Optimal Control *Halit Eren* 98-1

99 Electropneumatic and Electrohydraulic Instruments: Modeling of
Electrohydraulic and Electrohydrostatic Actuators
M. Pachter and C. H. Houpis 99-1

100 Explosion-Proof Instruments *Sam S. Khalilieh*100-1

101 Measurement and Identification of Brush, Brushless, and dc Stepping
Motors *Stuart Schweid, Robert Lofthus, John McInroy*.....101-1

Appendix Units and Conversions *B. W. Petley*.....A-1

IndexI-1